

Search Notes

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10/820,315

Examiner

Hieu P. Nguyen

Applicant(s)/Patent under
Reexamination

GREBENNIKOV ET AL.

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner
330	285	3/1/2006	HN
330	296	3/1/2006	HN
330	133	3/1/2006	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
MOTTOLA STEVEN J	3/1/2006	HN
EAST UPDATE SEARCH SEE PRINT OUT	3/1/2006	HN